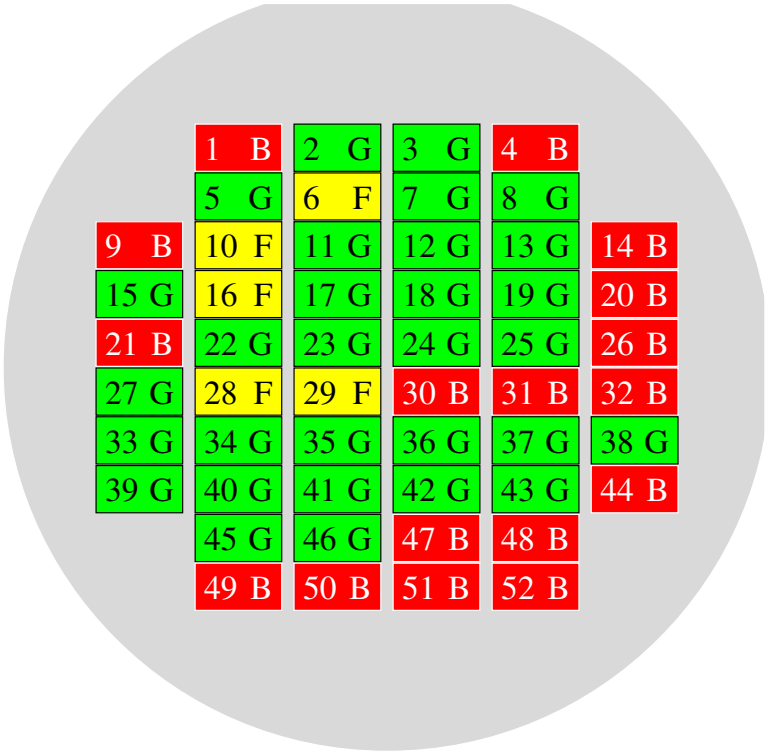
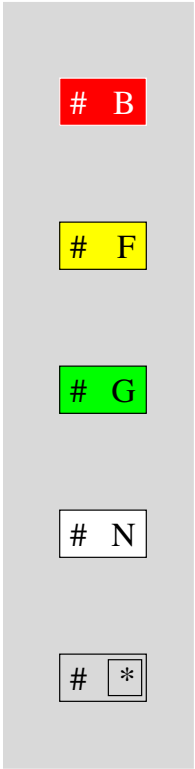
Die quality map for wafer 33 s/n: 21316-06-16

Date: 11/01/98